

**Notice of References Cited**

Application/Control No.

10/576,450

Applicant(s)/Patent Under  
Reexamination  
TSUDA ET AL.

Examiner

NICOLE M. BUIE

Art Unit

1796

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**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2003/0181572	09-2003	Tan et al.	524/502
*	B	US-2004/0192828	09-2004	Mitsuhashi et al.	524/544
*	C	US-2003/0130393	07-2003	Cavanaugh et al.	524/366
	D	US-			
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	M	US-			

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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	WO95033782A1	12-1995	WIPO	Araki et al.	
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**NON-PATENT DOCUMENTS**

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	U	machine translation of WO 95033782A1
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	W	
	X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.